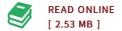


## Materials Issues for Tunable RF and Microwave Devices: Volume 603

By -

CAMBRIDGE UNIVERSITY PRESS, United Kingdom, 2014. Paperback. Book Condition: New. 229 x 152 mm. Language: English . Brand New Book \*\*\*\*\* Print on Demand \*\*\*\*\*. Electric or magnetic tunability of RF and microwave devices is desirable for a variety of civilian and military applications. Tremendous advances have been made in thin-film processing, in particular with metal-oxide thin films. Consequently, it has been recognized that the integration of nonlinear dielectric, ferrite, colossal magnetoresistive (CMR) ferromagnetic, and superconductor materials could revolutionize tunable devices by providing capabilities while significantly reducing size and cost. Crucial issues facing this technology concern the material properties, in particular, the loss in thin films of the tunable materials. Extensive efforts are being devoted to understand the tuning and loss mechanisms, improve thin-film processing and characterization, develop new materials, and design novel device concepts. This book, first published in 2000, serves as a reference for researchers and contributes to breakthroughs in basic and applied research in this field. Topics include: frequencyagile materials for electronics; electric-field tuning; magnetic-field tuning; high-frequency applications for ferroelectrics; ferroelectrics; magnetics and others; fundamentals and materials characterization.



## Reviews

This is basically the finest publication i actually have go through till now. We have read and i also am confident that i am going to likely to read through again once more in the foreseeable future. It is extremely difficult to leave it before concluding, once you begin to read the book. -- Prof. Adell Lubowitz

This kind of pdf is every little thing and taught me to looking forward and more. It is one of the most incredible book i have read. You wont truly feel monotony at whenever you want of your time (that's what catalogs are for about should you check with me). -- Miss Amelie Fritsch DVM